

Product Change Notification / MFOL-26MWUB160

Date:

05-Jan-2024

Product Category:

32-Bit Microcontrollers

PCN Type:

Manufacturing Change

Notification Subject:

CCB 6778 Initial Notice: Qualification of ANAP as an additional assembly site for selected AT91R40008, ATSAM3N0CA, ATSAM3N1CB, ATSAM3S1CB, ATSAM3S2CA, ATSAM3S4CA, and ATSAM3U1CB device families available in 100L LQFP (14x14x1.4mm) package.

Affected CPNs:

MFOL-26MWUB160_Affected_CPN_01052024.pdf MFOL-26MWUB160_Affected_CPN_01052024.csv

Notification Text:

PCN Status:Initial Notification

PCN Type: Manufacturing Change

Microchip Parts Affected:Please open one of the files found in the Affected CPNs section. Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:Qualification of ANAP as an additional assembly site for selected AT91R40008, ATSAM3N0CA, ATSAM3N1CB, ATSAM3S1CB, ATSAM3S2CA, ATSAM3S4CA, and ATSAM3U1CB device families available in 100L LQFP (14x14x1.4mm) package.

Pre and Post Change Summary:

		Pre Change		Change					
Asseml	oly Site	ATX Semiconductor (Shanghai) Co. Ltd (ASSH)		conductor ii) Co. Ltd SH)	Amkor Technology Philippine (P1/P2), INC. (ANAP)				
Wire Material		Au	A	u	Au				
Die Attack	n Material	2288A	228	38A	3230				
Molding C Mat	ompound erial	CEL-9200THF	CEL-9200THF		G631HQ				
	Material	C7025	C7()25	C194ESH				
Lood Frame	Lead-lock	No	No		Yes				
Lead-Frame	Paddle Size	180X180 240X240	180X180	240X240	256X256				
	Paulie Size	See pre and post change for comparison.							

Impacts to Data Sheet:None

Change Impact:None

Reason for Change:To improve on-time delivery performance by qualifying ANAP as an assembly site.

Change Implementation Status: In Progress

Estimated Qualification Completion Date:May 2024

Note: Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date. Also note that after the estimated first ship date guided in the final PCN customers may receive pre and post change parts.

Time Table Summary:

	January 2024					>	May 2024					
Workweek	0 1	0 2	0 3	0 4	0 5		18	19	20	21	22	
Initial PCN Issue Date	Х											
Qual Report Availability									х			
Final PCN Issue Date									х			

Method to Identify Change: Traceability code

Qualification Plan: Please open the attachments included with this PCN labeled as PCN_#_Qual_Plan.

Revision History: January 05, 2024: Issued initial notification.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachments:

PCN_MFOL-26MWUB160_Pre and Post Change Summary.pdf PCN_MFOL-26MWUB160_Qual Plan.pdf

Please contact your local Microchip sales office with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our PCN home page select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the PCN FAQ section.

If you wish to <u>change your PCN profile, including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections. MFOL-26MWUB160 - CCB 6778 Initial Notice: Qualification of ANAP as an additional assembly site for selected AT91R40008, ATSAM3N0CA, ATSAM3N1CB, ATSAM3S1CB, ATSAM3S2CA, ATSAM3S4CA, and ATSAM3U1CB device families available in 100L LQFP (14x14x1.4mm) package.

Affected Catalog Part Numbers (CPN)

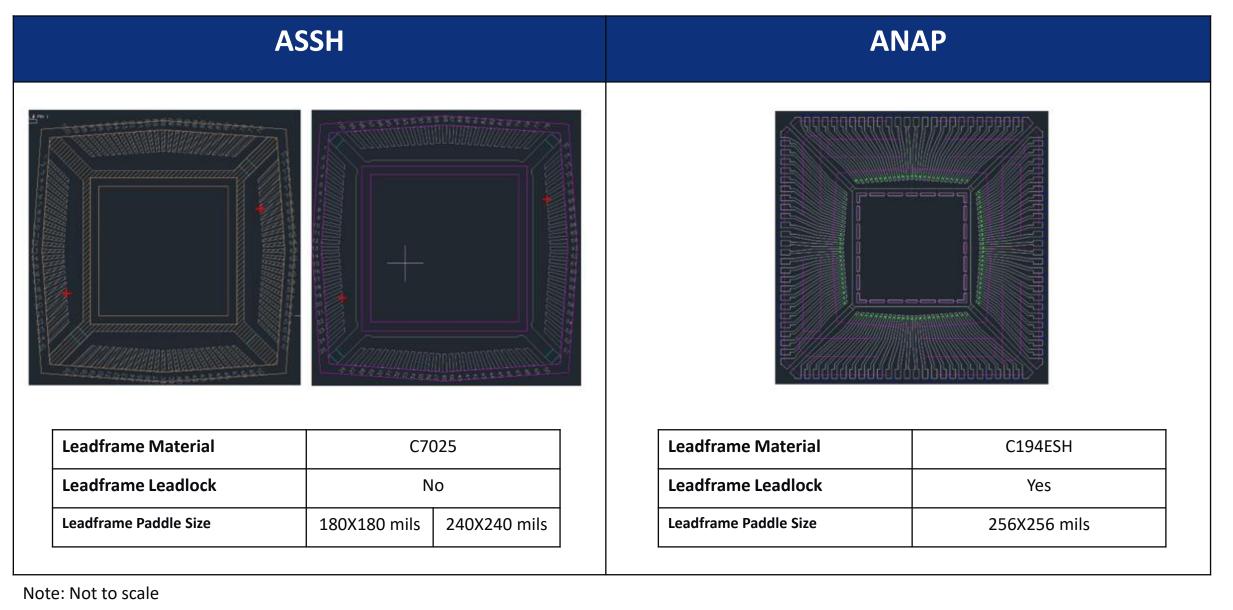
ATSAM3N1CB-AU ATSAM3N1CB-AUR ATSAM3N0CA-AU ATSAM3N0CA-AUR AT91R40008-66AU AT91R40008-66AU-999 ATSAM3S2CA-AU ATSAM3S2CA-AUR ATSAM3S4CA-AUR ATSAM3S4CA-AUR ATSAM3U1CB-AU ATSAM3S1CB-AUR



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Pre and Post Summary – Leadframe Comparison







PCN #: MFOL-26MWUB160

Date: December 21, 2023

Qualification of ANAP as an additional assembly site for selected AT91R40008, ATSAM3N0CA, ATSAM3N1CB, ATSAM3S1CB, ATSAM3S2CA, ATSAM3S4CA, and ATSAM3U1CB device families available in 100L LQFP (14x14x1.4mm) package.

- **Purpose:** Qualification of ANAP as an additional assembly site for selected AT91R40008, ATSAM3N0CA, ATSAM3N1CB, ATSAM3S1CB, ATSAM3S2CA, ATSAM3S4CA, and ATSAM3U1CB device families available in 100L LQFP (14x14x1.4mm) package.
- **CCB No.** 6778

	Assembly site	ANAP					
	BD Number	BD-002072-01					
	MP Code (MPC)	58A907H7XC03					
	Part Number (CPN)	AT91R40008-66AU					
<u>Misc.</u>	MSL information	MSL3					
	Assembly Shipping Media (T/R, Tube/Tray)	Тгау					
	Base Quantity Multiple (BQM)	90/Tray					
	Reliability Site	MPHIL					
	Paddle size	256X256					
	Material	C194ESH					
	DAP Surface Prep	Double Ring Ag					
	Treatment	Non-roughened					
	Process	Stamped					
Lead-Frame	Lead-lock	Yes					
	Part Number	101423138					
	Lead Plating	Matte Sn					
	Strip Size	80x250mm					
	Strip Density	UDLF					
Bond Wire	Material	Au					
	Part Number	3230					
Die Attach	Conductive	Yes					
MC	Part Number	G631HQ					
	Package Type	LQFP					
PKG	Pin/Ball Count	100					
<u></u>	PKG width/size	14x14x1.4mm					

Test Name	Conditions	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	ATE Test Site	REL test site	Special Instruction
Standard Pb- free Solderability	J-STD-002D; Perform 8-hour steam aging for Matte tin finish and 1 hour steam aging for NiPdAu finish prior to testing. Standard Pb-free: Matte tin/ NiPdAu finish, SAC solder, wetting temp 245°C for both SMD & through hole packages.	22	5	1	27	> 95% lead coverage	5			Standard Pb-free solderability is the requirement. SnPb solderability (backward solderability- SMD reflow soldering) is required for any plating related changes and highly recommended for other package BOM changes.
Wire Bond Pull - WBP	Mil. Std. 883-2011	5	0	1	5	0 fails after TC	5			30 bonds from a min. 5 devices.
Wire Bond Shear - WBS	CDF-AEC-Q100-001	5	0	1	5	0	5			30 bonds from a min. 5 devices.
Physical Dimensions	Measure per JESD22 B100 and B108	10	0	3	30	0	5			
External Visual	Mil. Std. 883-2009/2010	All devices prior to submission for qualification testing	0	3	ALL	0	5			
Preconditioning - Required for surface mount devices	JESD22-A113. +150°C Bake for 24 hours, moisture loading requirements per MSL level + 3X reflow at peak reflow temperature per Jedec-STD- 020E for package type; Electrical test pre and post stress at +25°C.	231	15	3	738	0	15	ASE9	MPHIL	Spares should be properly identified. 77 parts from each lot to be used for HAST, uHAST, Temp Cycle test.
HAST	JESD22-A110. +130°C/85% RH for 96 hours or 110°C/85%RH for 264 hours. Electrical test pre and post stress at +25°C and hot temp (85°C).	77	5	3	246	0	10	ASE9	MPHIL	Spares should be properly identified. Use the parts which have gone through Pre- conditioning.
UHAST	JESD22-A118. +130°C/85% RH for 96 hrs or +110°C/85%	77	5	3	246	0	10	ASE9	MPHIL	Spares should be properly identified.

Test Name	Conditions	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	ATE Test Site	REL test site	Special Instruction
	RH for 264 hrs. Electrical test pre and post stress at +25°C									Use the parts which have gone through Pre- conditioning.
Temp Cycle	JESD22-A10465°C to +150°C for 500 cycles. Electrical test pre and post stress at hot temp (85°C); 3 gram force WBP, on 5 devices from 1 lot, test following Temp Cycle stress.	77	5	3	246	0	15	ASE9	MPHIL	Spares should be properly identified. Use the parts which have gone through Pre- conditioning.